

Notice of References Cited	Application/Control No. 10/707,584		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Matthew G. Kayrish		Art Unit 2653	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0018426	02-2002	Minase, Minoru	369/75.2
*	B	US-6,181,663	01-2001	Kakuta et al.	720/610
*	C	US-6,665,253	12-2003	Lan et al.	720/659
*	D	US-6,775,093	08-2004	Smith et al.	360/92
*	E	US-2001/0055178	12-2001	STABILE et al.	360/94
*	F	US-2003/0043720	03-2003	Fujisawa, Shinichi	369/75.2
*	G	US-2004/0205787	10-2004	Wu, Jen-Chen	720/610
*	H	US-6,246,540	06-2001	Kabasawa, Hidetoshi	360/99.06
*	I	US-5,585,978	12-1996	Rottenburg et al.	360/85
*	J	US-5,563,865	10-1996	Wheeler, Arthur R.	720/608
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003331499 A	11-2003	Japan	IDEMIYA, YUSUKE	G11B 17/04
	O	JP 2004185762 A	07-2004	Japan	KAMIYAMA et al.	G11B 17/04
	P	JP 2004303289 A	10-2004	Japan	SHINOHARA et al.	G11B 17/04
	Q	JP 06068572 A	03-1994	Japan	SOGA et al.	G11B 17/04
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.